

Search Notes



Application/Control No.

10/757,115

Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

SMITH ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	108	01.13.05	Mr
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Updated Search		07.06.05	Mr

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	01.13.05	Mr